

<b>Notice of References Cited</b>	Application/Control No. 10/050,207		Applicant(s)/Patent Under Reexamination BERNSTEIN ET AL.	
	Examiner Yubin Hung		Art Unit 2625	Page 1 of 1

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	V	Morris et al., "A Sampling Based Approach to Line Scratch Removal from Motion Picture Frames," Proc. Of the Int'l Conf. on Image Processing, Vol. 1, 16-19 Sep. 1996, pp. 801-804			
	W	Joyeux et al., "Film Line Scratch Removal Using Kalman Filtering and Bayesian Restoration," 5th IEEE Workshop on Applications of Computer Vision, 4-6 Dec. 2000, pp. 8-13			
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.